

**Search Notes**

Application/Control No.

10/618,552

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

YAKURA ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
updated	updated	5/4/2005	<i>SWH</i> SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
347	29,23	5/4/2005	<i>SWH</i> SWH
347	30,33	5/4/2005	<i>SWH</i> SWH
347	35	5/4/2005	<i>SWH</i> SWH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR